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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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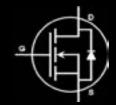




eGaN® FET DATASHEET EPC2018

EPC2018 – Enhancement Mode Power Transistor

 V_{DSS} , 150 V $R_{DS(ON)}$, $25\,m\Omega$ I_D , 12 A









Gallium Nitride is grown on Silicon Wafers and processed using standard CMOS equipment leveraging the infrastructure that has been developed over the last 55 years. GaN's exceptionally high electron mobility and low temperature coefficient allows very low R_{DS(ON)}, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings					
V_{DS}	Drain-to-Source Voltage	150	V		
I _D	Continuous ($T_A = 25^{\circ}C$, $\theta_{JA} = 17$)	12	А		
	Pulsed (25°C, Tpulse = 300 μs)	60			
V _{GS}	Gate-to-Source Voltage	6	V		
	Gate-to-Source Voltage	-5			
Tı	Operating Temperature	-40 to 125	°C		
T _{STG}	Storage Temperature	-40 to 150			



EPC2018 eGaN® FETs are supplied only in passivated die form with solder bars

Applications

- High Speed DC-DC conversion
- · Class D Audio
- Hard Switched and High Frequency Circuits

Benefits

- · Ultra High Efficiency
- Ultra Low R_{DS(on)}
- Ultra low Q_G
- · Ultra small footprint

PARAMETER		TEST CONDITIONS	MIN	ТҮР	MAX	UNIT	
Static Character	Static Characteristics (T _j = 25°C unless otherwise stated)						
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, } I_D = 200 \mu\text{A}$	150			V	
I _{DSS}	Drain Source Leakage	$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V}$		50	150	μΑ	
	Gate-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	3	mA	
I _{GSS}	Gate-Source Reverse Leakage	$V_{GS} = -5 \text{ V}$		0.2	1		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 3 \text{ mA}$	0.7	1.4	2.5	V	
R _{DS(ON)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_{D} = 6 \text{ A}$		18	25	m $Ω$	
Source-Drain Ch	Source-Drain Characteristics (T _J = 25°C unless otherwise stated)						
V	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}, T = 25^{\circ}\text{C}$		1.8		V	
V_{SD}		$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}, T = 125 ^{\circ}\text{C}$		1.8		l v	

	Thermal Characteristics		
		TYP	
$R_{ heta JC}$	Thermal Resistance, Junction to Case	2.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	16	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	56	°C/W

Note 1: R_{DA} is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

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	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT	
Dynamic Chara	Dynamic Characteristics (T _j = 25°C unless otherwise stated)						
C _{ISS}	Input Capacitance			480	540		
Coss	Output Capacitance	$V_{DS} = 100 V, V_{GS} = 0 V$		270	350	pF	
C _{RSS}	Reverse Transfer Capacitance			9.2	12		
Q_G	Total Gate Charge (V _{GS} = 5 V)			5	7.5		
Q_{GD}	Gate to Drain Charge	$V_{DS} = 100 \text{ V}, I_{D} = 12 \text{ A}$		1.7	2.6		
Q_{GS}	Gate to Source Charge			1.3	2	nC	
Q _{oss}	Output Charge	$V_{DS} = 100 V, V_{GS} = 0 V$		40	50		
Q_{RR}	Source-Drain Recovery Charge			0			

All measurements were done with substrate shorted to source.



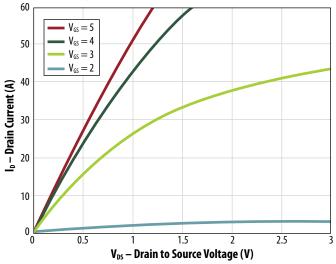


Figure 2: Transfer Characteristics

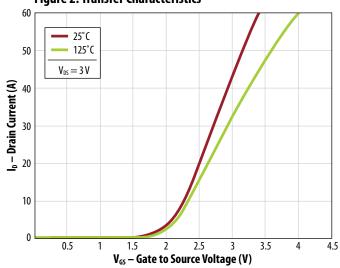


Figure 3: R_{DS(ON)} vs V_G for Various Current

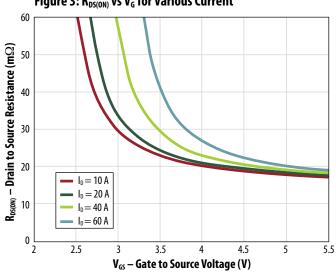
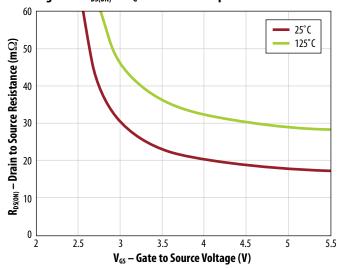
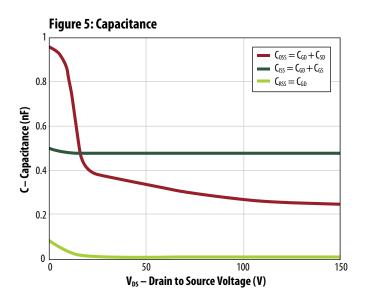


Figure 4: R_{DS(ON)} vs V_G for Various Temperature



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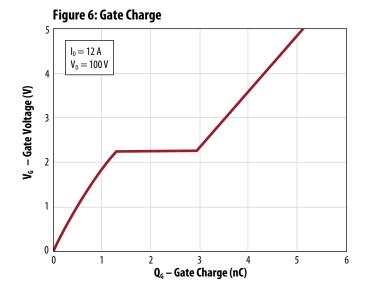
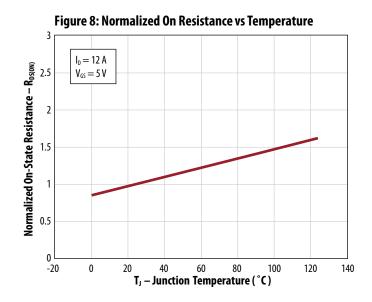
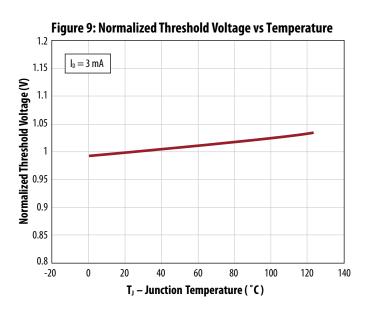
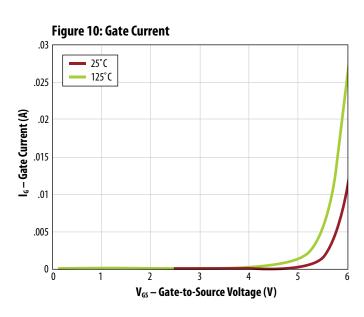


Figure 7: Reverse Drain-Source Characteristics 60 25°C 125°C 50 I₅₀ – Source to Drain Current (A) 40 30 20 10 0 6 1.5 2 2.5 3 V_{sp} – Source to Drain Voltage (V) 0.5 3.5 4 4.5



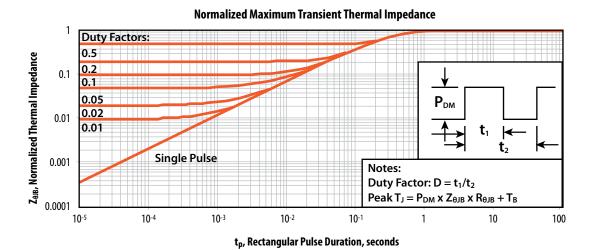




All measurements were done with substrate shortened to source.

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Figure 11: Transient Thermal Response Curves



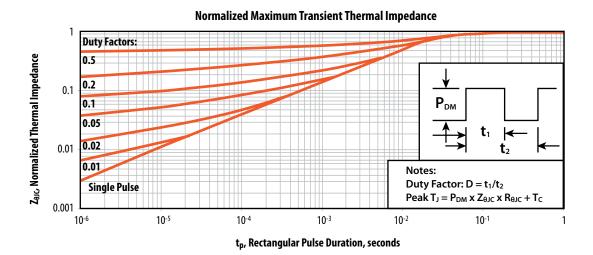
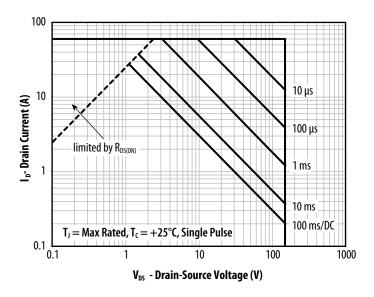
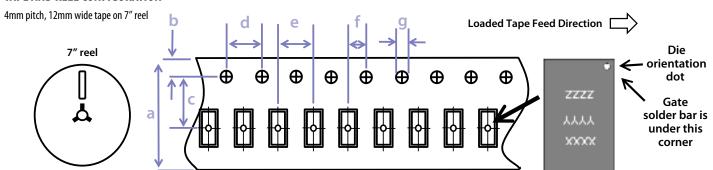


Figure 12: Safe Operating Area



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TAPE AND REEL CONFIGURATION

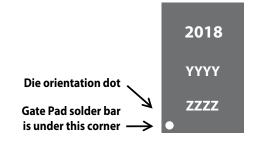


EPC2018 (note 1) Dimension (mm) target min 11.9 12.3 12.0 b 1.75 1.65 1.85 5.45 c (note 2) 5.50 5.55 d 4.00 3.90 4.10 4.00 3.90 4.10 e f (note 2) 2.00 1.95 2.05 g 1.5 1.5 1.6

Die is placed into pocket solder bar side down (face side down)

Note 1: MSL1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard. Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

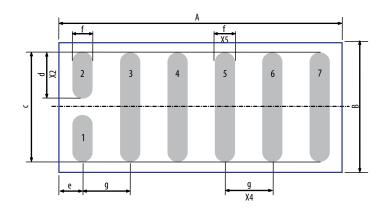
DIE MARKINGS



Dout		Laser Markings	
Part Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
	Marking Line 1	Marking line 2	Marking Line 3
EPC2018	2018	YYYY	ZZZZ

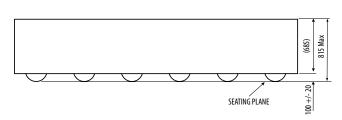
DIE OUTLINE

Solder Bar View



DIM	MICROMETERS				
DIM	MIN	Nominal	MAX		
Α	3524	3554	3584		
В	1602	1632	1662		
C	1379	1382	1385		
d	577	580	583		
e	262	277	292		
f	245	250	255		
g	600	600	600		

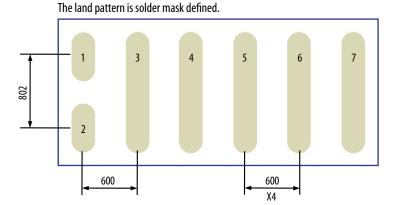
Side View



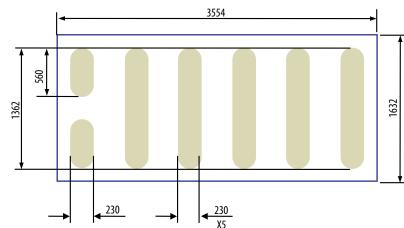
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RECOMMENDED LAND PATTERN

(units in µm)



Pad no. 1 is Gate; Pads no. 3, 5, 7 are Drain; Pads no. 4, 6 are Source; Pad no. 2 is Substrate



Additional assembly resources available at epc-co.com/AssemblyBasics

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 $eGaN^{\circledast}$ is a registered trademark of Efficient Power Conversion Corporation.

U.S. Patents 8,350,294; 8,404,508; 8,431,960; 8,436,398

Information subject to change without notice. Revised August, 2013